

,	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/735,290	NAGAI ET AL.
	Examiner	Art Unit
	Michael V Won	2155

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	205, 206, 207	11/28/2007	MW
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
709	206	11/28/2007	MW		

SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
EAST: USPAT; SUPG-PUB; DERWENT; EPO; JPO	11/28/2007	MW
NPL SEARCH: IEEE & GOOGLE	11/28/2007	MW
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